

pininfarina

Global Network AUTOMOTIVE AUTOMOTIVE ARCHITECTURE ENGINEERING & PRODUCT TRANSPORTATION ENGINEERING & PRODUCT ARCHITECTURE & PRODUCT ENGINEERING TRANSPORTATION WIND TUNNEL **TRANSPORTATION** AUTOMOTIVE

beauty x performance = impact

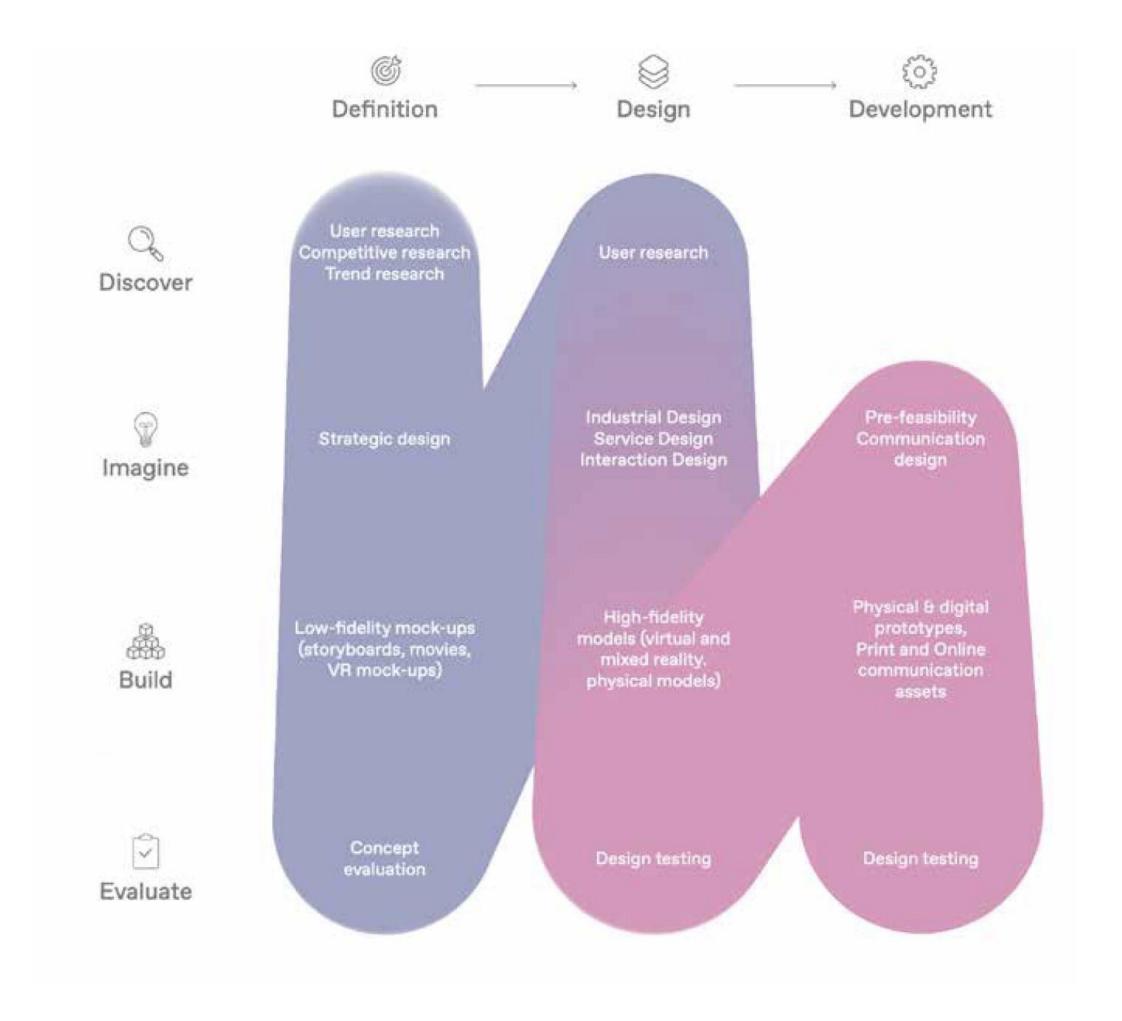
Methodology

Pininfarina Product Design's methodology implies a collaborative, iterative, and user-centric approach, hence committing to a nonlinear cycle of improvements implemented – until thought fit – throughout every stage of project iteration.

The overarching objective is to meticulously define the KEIs (Key Experience Indicators) that ultimately become the benchmark for the success of the design efforts. These indicators are qualitative and require a thorough journey of exploration.

Strictly speaking Pininfarina has a matrix methodology where definition, design and development (of a project) cross over actions such as exploration, imagination, construction and evaluation. These are made to happen in several stratifications, or rather iterations.

The iterative design process

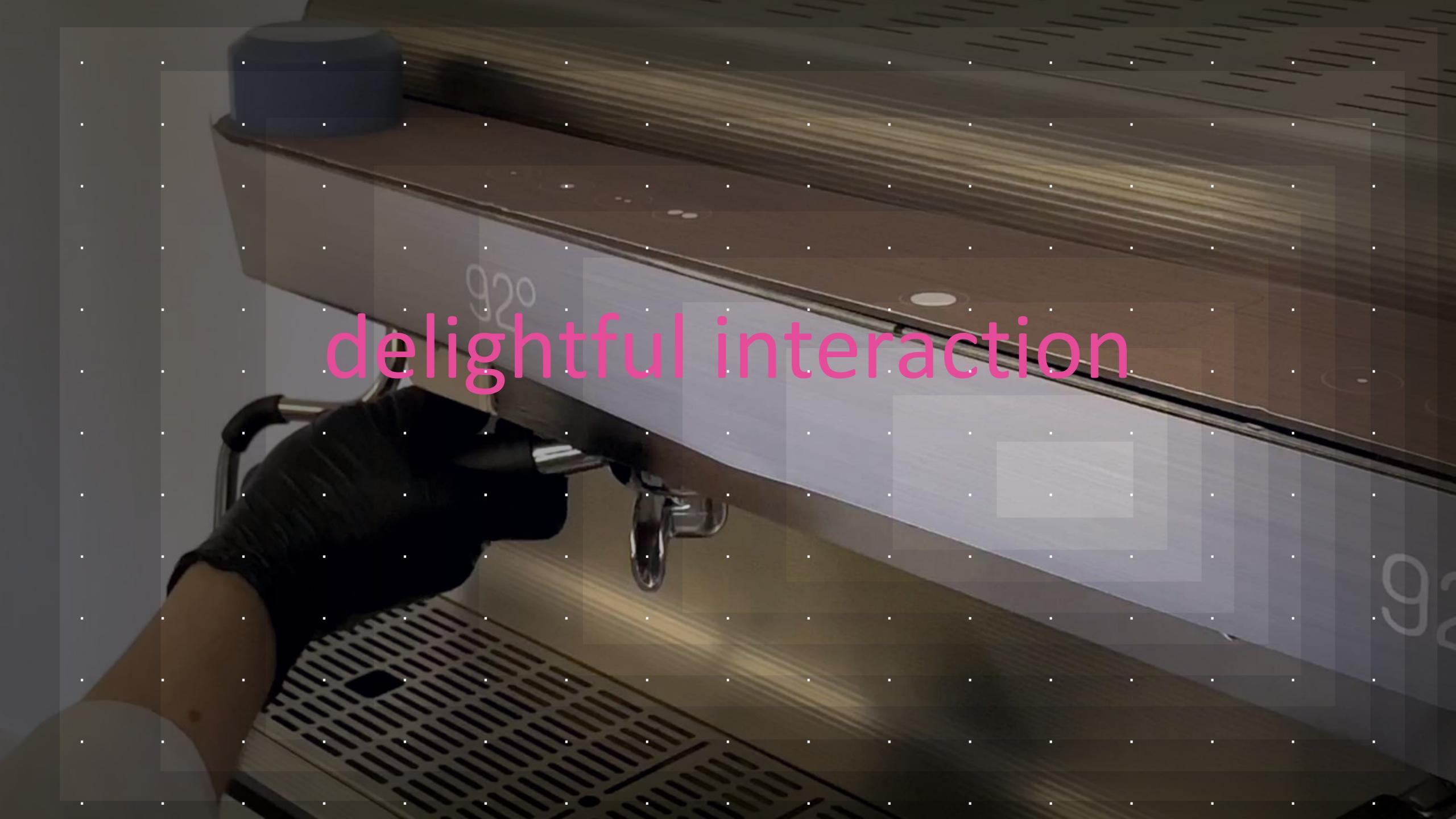


what we believe in

PROD UCT · DESIGN



essential beauty





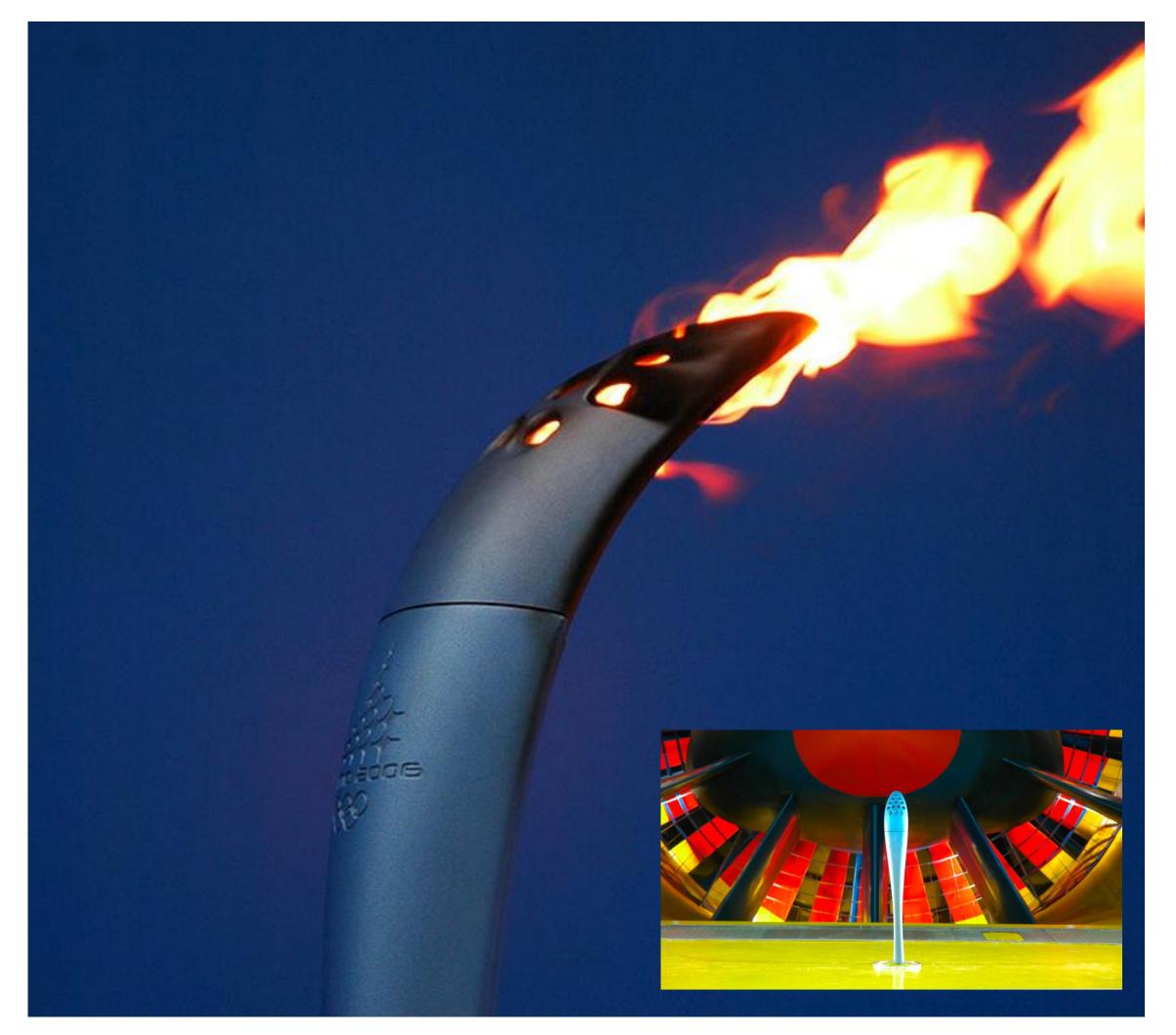


what we bring

le design & deliver amazing product experiences, tangible and intangible

How we do it

cross-pollination & collaboration

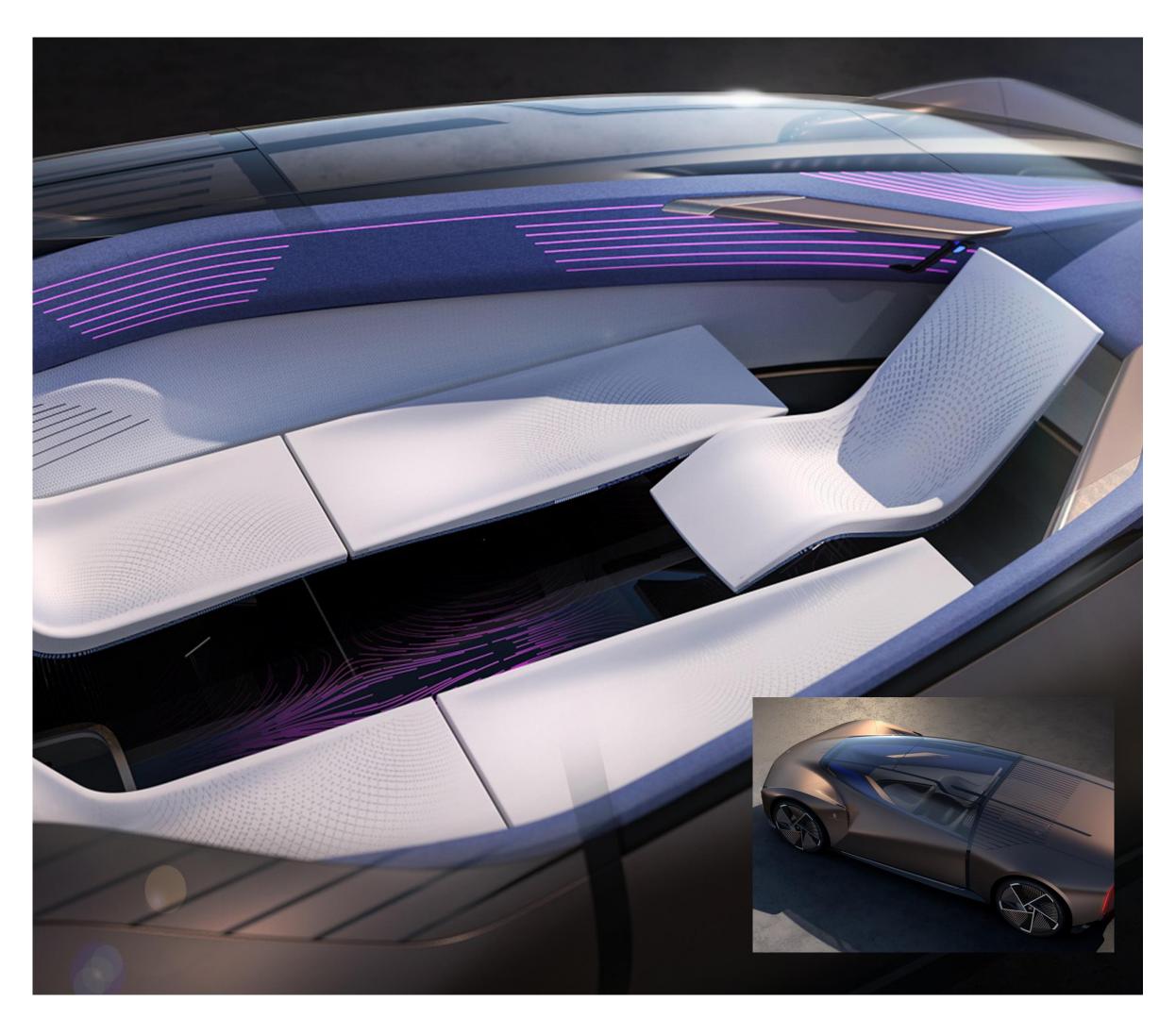






technology as enabler







holistic sustainability







•	• • 30 VIA NAZIONALE,	•	•	•	•	•	•	•	•	•	•	pininfa	pininfarina.com		
	CAMBIANO, TO - ITAL	Y 10020													
•	T+39 011 9438111	•	•	•	•	•	•	•	•	•	•	•	•		•
	34 VIA BORGOGNONI														
•	MILANO, MI – ITALY 2	20144	•	•	•	•	•	•	•	•	•	•	•	•	•
501 BRICK	501 BRICKELL KEY DR		•	•	•	•		•	•						•
	MIAMI, FL – USA 3313 T +1 305 424 1653	31													
•		•	•	•	•	•	•	•	•	•	•				•
	114 W 26TH STREET,														
	NEW YORK, NY – USA	. 10001													
	UNIT 1, BUILDING 3, LANE 56, ANTUO ROAD,														
	ANTING, JIADING, SHA	ANGHAI - CHINA 20	1805	•	•	•	•	•	•	•	•	•	•	•	•
	T +86 18917474758														
•		•	•	•	•	•	•	•	•	•	•			•	•
												PR	(OD)		
												i i C	, T.		
													<i>,</i>		
												DF	SIGI	V	
•	•	•	•	•	•	•	•	•	•	•	•				•
												pin	infani		